

N-Channel Power MOSFET

50A, 60V, 0.023Ω

GENERAL DESCRIPTION

This N-Channel MOSFET is used an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance. This device is well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based half bridge topology.

FEATURES

- Avalanche energy specified
- Gate Charge (Typical 36nC)
- High Ruggedness

ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ\text{C}$, unless otherwise noted)

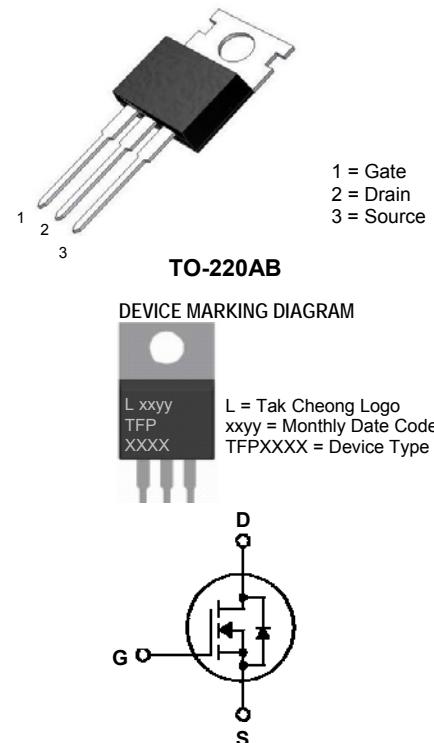
Symbol	Parameter	Value	Units
V_{DSS}	Drain- Source Voltage	60	V
V_{GSS}	Gate-Source Voltage	± 25	V
I_D	Drain Current	50	A
I_{DM}	Drain Current Pulsed	200	A
P_D	Power Dissipation (Note 2)	120	W
	Derating Factor above 25°C	0.8	W/ $^\circ\text{C}$
E_{AS}	Single Pulsed Avalanche Energy (Note 1)	642	mJ
E_{AR}	Repetitive Avalanche Energy (Note 2)	12	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	7.0	V/ns
T_J	Operating Junction Temperature	150	$^\circ\text{C}$
T_{stg}	Storage Temperature Range	- 55 to +150	$^\circ\text{C}$

Notes:

1. $L=30\mu\text{H}$, $I_{AS}=50\text{A}$, $V_{DD}=25\text{V}$, $R_G=50\Omega$, Starting $T_J=25^\circ\text{C}$.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. $I_{SD} \leq 50\text{A}$, $dI/dt \leq 300\text{A/us}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.25	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ\text{C/W}$



ELECTRICAL CHARACTERISTICS
Off Characteristics ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	60	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60V, V_{GS} = 0V$	--	--	1	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 25V, V_{DS} = 0V$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25V, V_{DS} = 0V$	--	--	-100	nA

On Characteristics ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	--	4.0	V
$R_{DS(\text{ON})}$	On-Resistance	$V_{GS} = 10V, I_D = 25A$	--	0.017	0.023	Ω

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V, f = 1.0\text{MHz}$	--	---	1460	pF
C_{oss}	Output Capacitance		--	---	580	pF
C_{rss}	Reverse Transfer Capacitance		--	---	90	pF

Switching Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 30V, I_D = 25A, R_G = 25\Omega$ (Note 4 & 5)	--	50	--	nS
t_r	Turn-On Rise Time		--	165	--	nS
$t_{d(off)}$	Turn-Off Delay Time		--	78	--	nS
t_f	Turn-Off Fall Time		--	60	--	nS
Q_g	Total Gate Charge	$V_{DS} = 160V, I_D = 8.0A, V_{GS} = 10V$ (Note 4 & 5)	--	36	45	nC
Q_{gs}	Gate-Source Charge		--	8.5	--	nC
Q_{gd}	Gate-Drain Charge		--	12	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Drain-Source Current	Integral Reverse p-n Junction Diode in the MOSFET	--	--	50	A
I_{SM}	Pulsed Drain-Source Current		--	--	200	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0V, I_S = 50A$	--	--	1.5	V
T_{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_S = 50A, dI_F / dt = 100A/\mu s$	--	95	--	nS
Q_{rr}	Reverse Recovery Charge	(Note 4)	--	250	--	μC

Notes:

4. Pulse Test: Pulse width < 300us, Duty cycle ≤ 2%.
5. Basically not affected by working temperature.

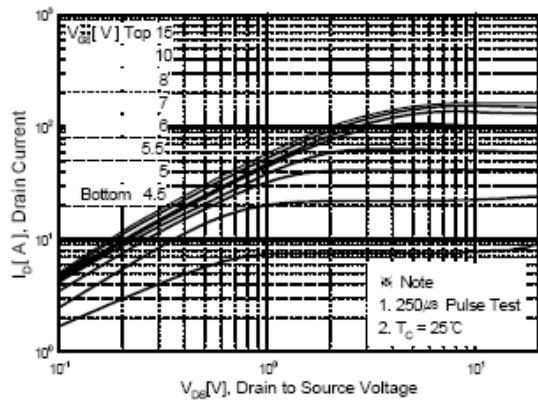
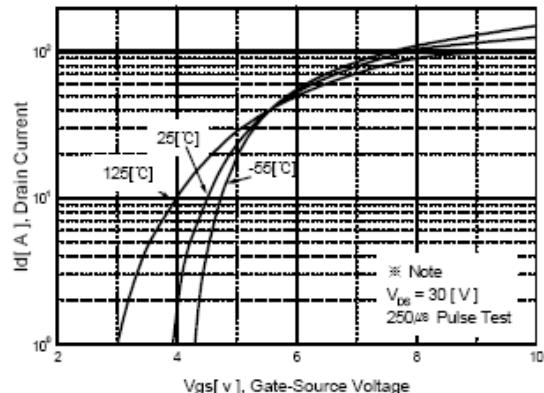
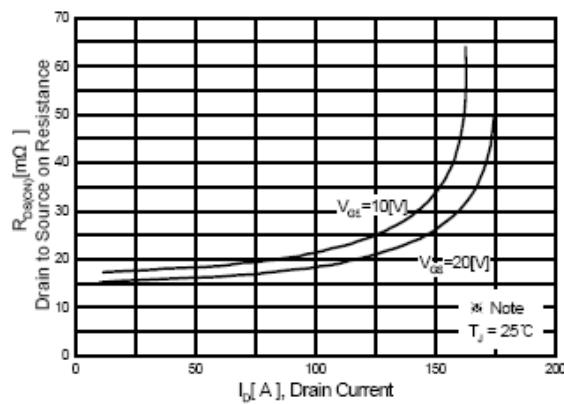
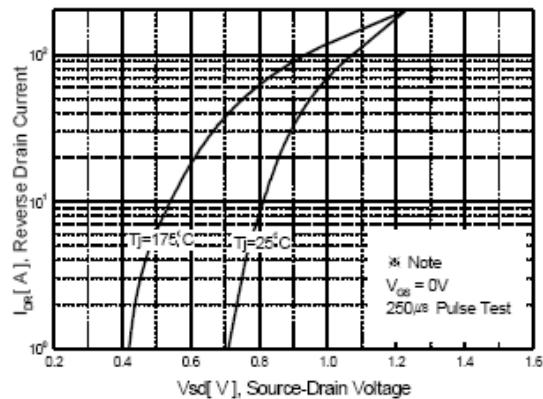
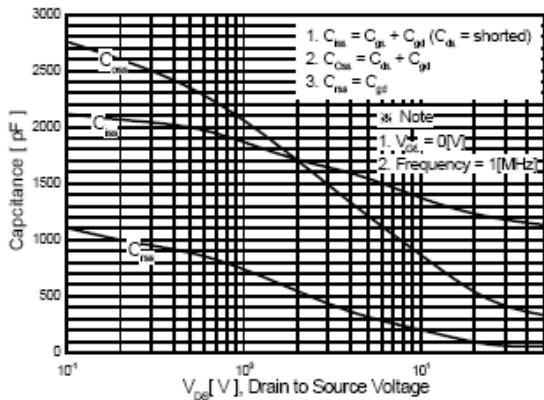
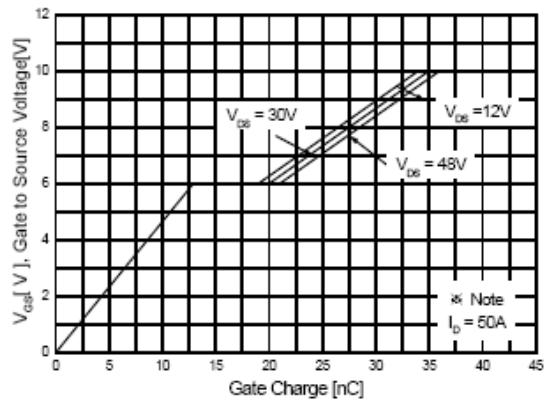
TYPICAL CHARACTERISTICS
Fig 1. On-State Characteristics

Fig 2. Transfer Characteristics

Fig 3. On Resistance Variation vs. Drain Current and Gate Voltage

Fig 4. On State Current vs. Allowable Case Temperature

Fig 5. Capacitance Characteristics

Fig 6. Gate Charge Characteristics


Fig 7. Breakdown Voltage variation vs. Temperature

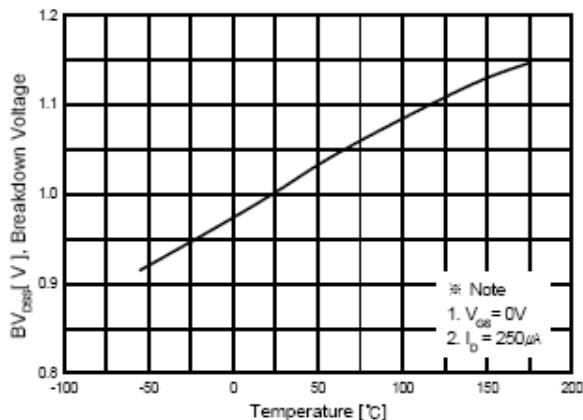


Fig 8. On Resistance variation vs. Temperature

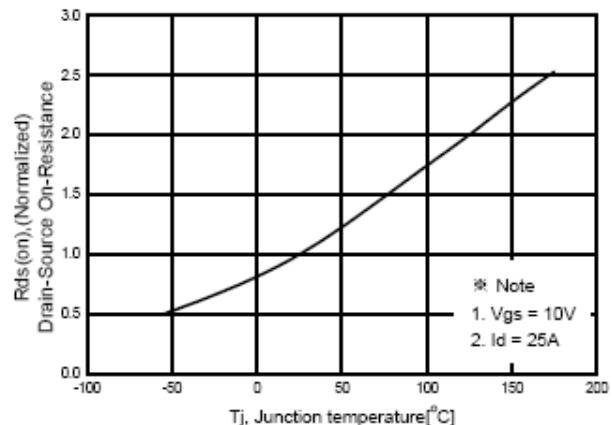


Fig 9. Maximum Safe Operating Area

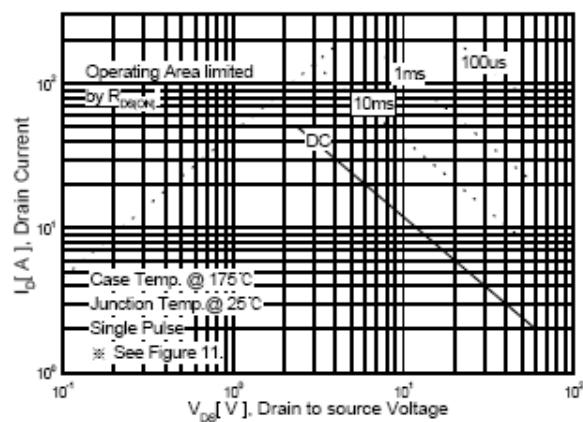


Fig 10. Maximum Drain Current vs. Case Temperature

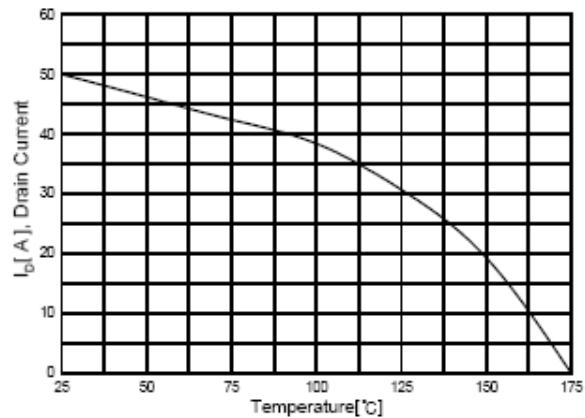


Fig 11. Transient Thermal Response Curve

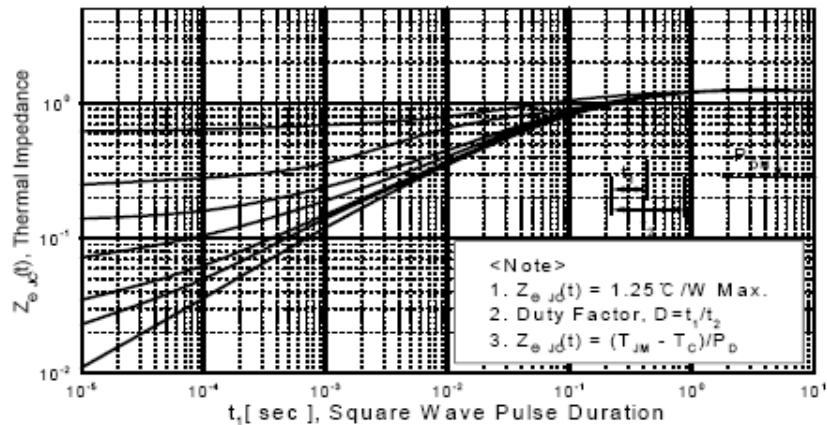


Fig. 12. Gate Charge Test Circuit & Waveforms

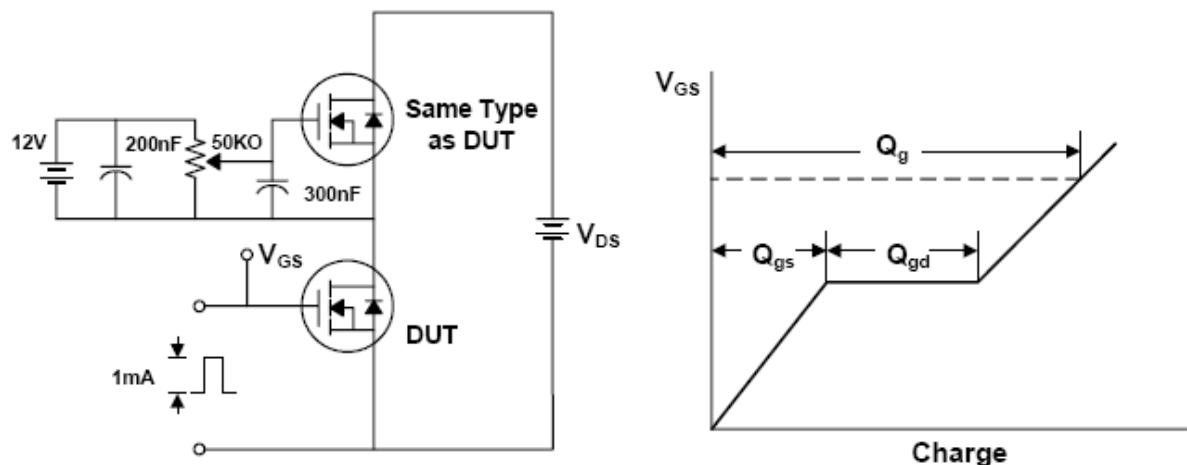


Fig 13. Switching Time Test Circuit & Waveforms

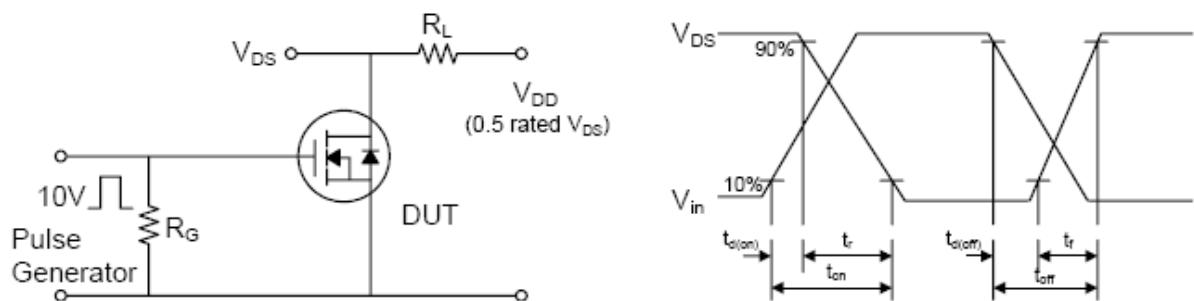


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

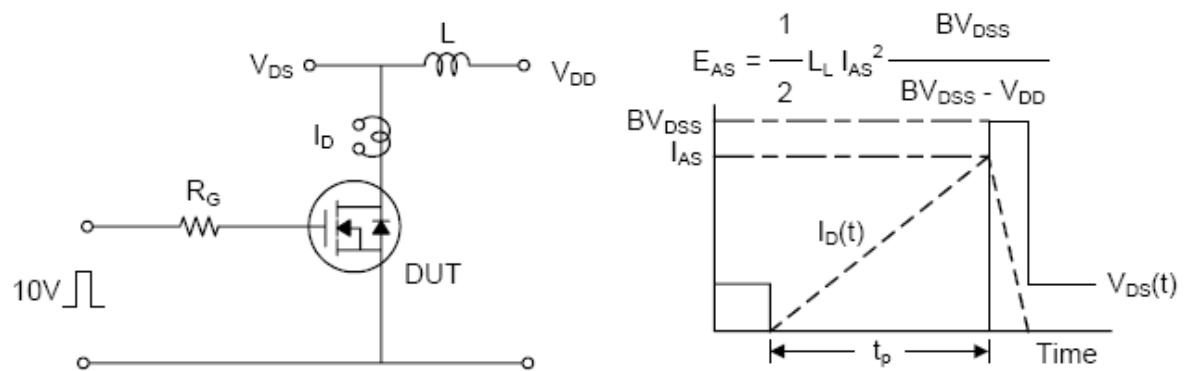
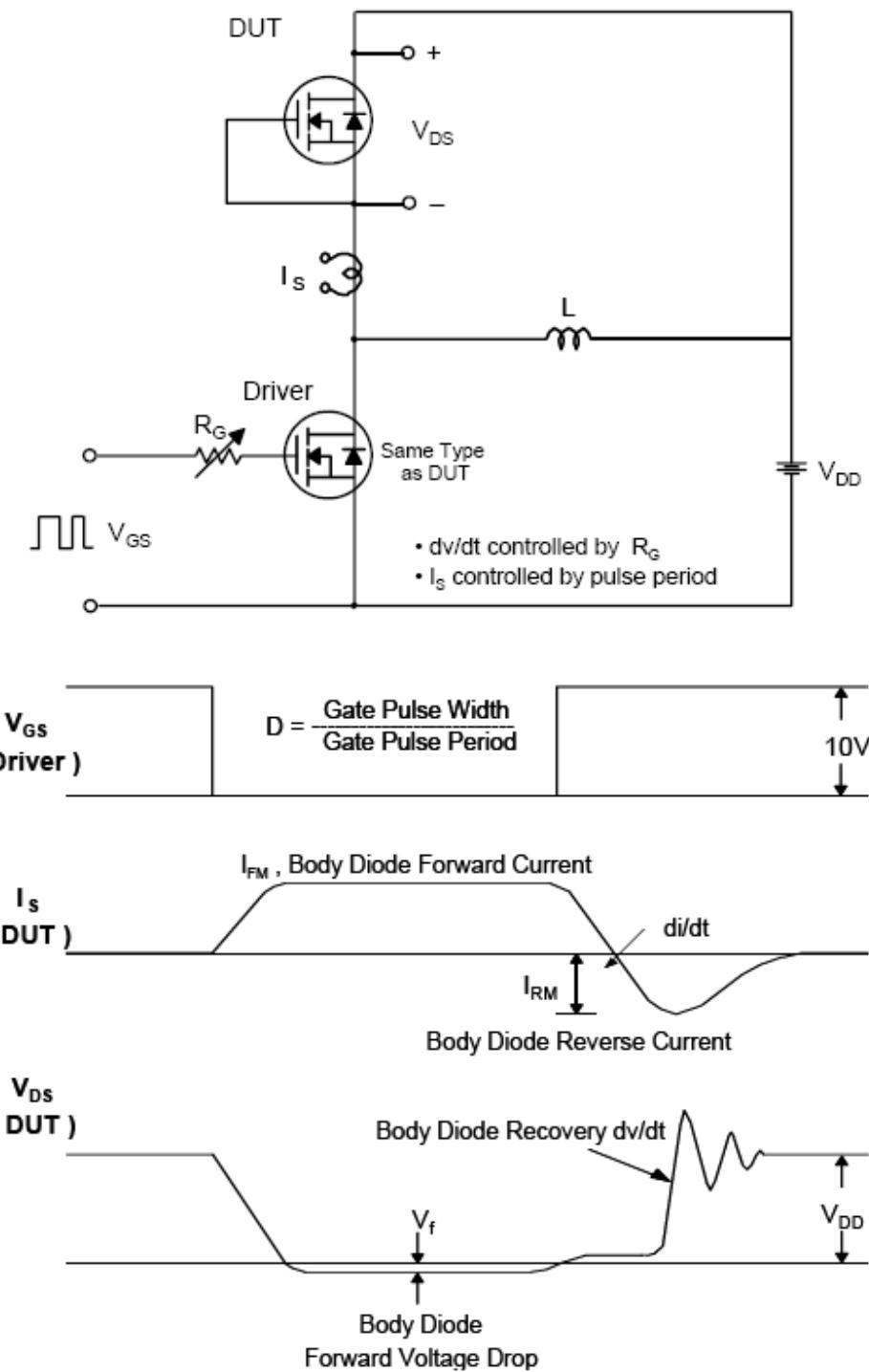
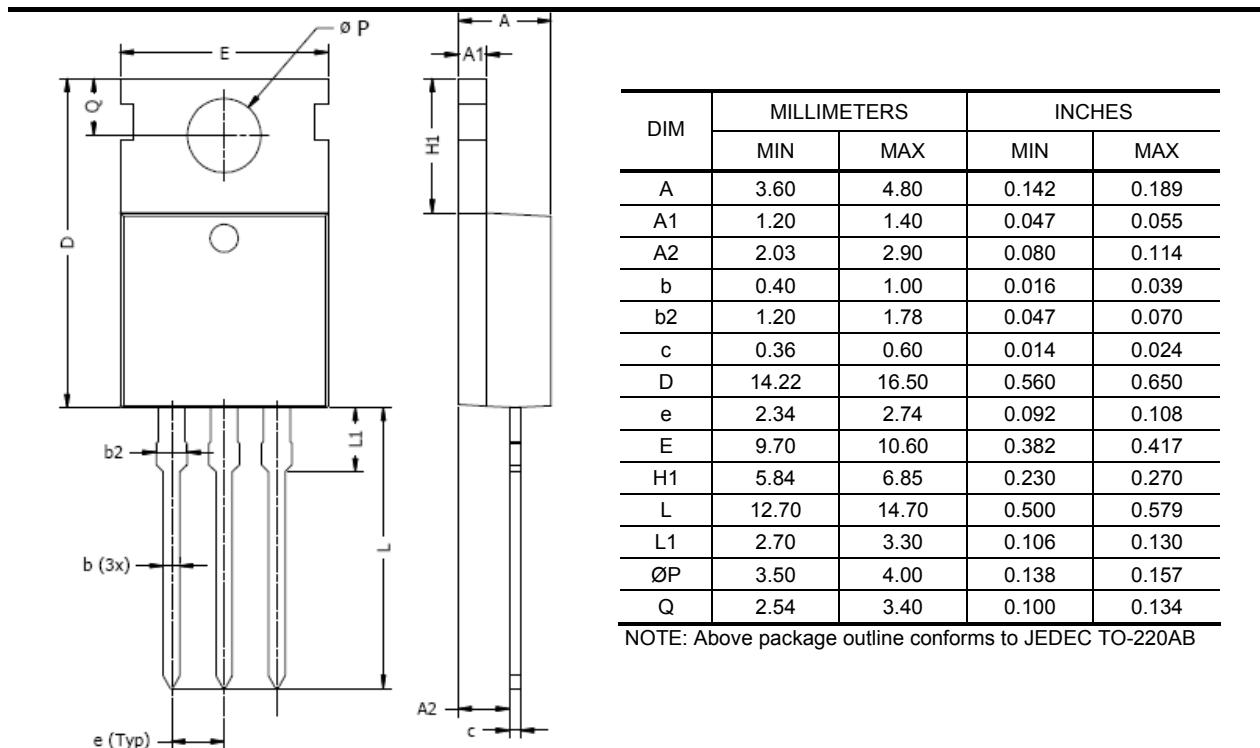


Fig. 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



TO220AB PACKAGE OUTLINE




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